



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR § 1.56, § 1.97, and § 1.98 FORM PTO-1449 Sheet 1 of 1	APPLICATION SERIAL NO.: 10/623,364	ATTORNEY DOCKET NO.: 38203-6215
	APPLICANTS: A. Smith et al.	
	FILING DATE: July 18, 2003	GROUP ART UNIT: 2872

U.S. PATENT DOCUMENTS						
† EX'R INITIAL	*REF. #	PATENT NUMBER	DATE	NAME	U.S. CLASS/ SUBCLASS	FILING DATE (If appropriate)
PK	A*	5,828,455	10/27/1998	Smith et al.	356/354	03/07/1997
PK	B*	5,978,085	11/02/1999	Smith et al.	356/354	10/23/1997

FOREIGN PATENT DOCUMENTS					
† EX'R INITIAL	*REF. #	DOCUMENT NO.	DATE	COUNTRY	TRANSLATION (YES/NO)
		NONE			

NON-PATENT DOCUMENTS		
† EX'R INITIAL	*REF. #	CITATION (Author, Article Title, Journal/Book Title, Date, Pertinent Pages, etc.)
PK	C	Y. Shiode et al., "Method of Zernike Coefficients Extraction for Optics Aberration Measurement", SPIE, Vol. 4691, 2002, pp. 1453-1464.

EXAMINER'S SIGNATURE 	DATE CONSIDERED 5/26/04
† EXAMINER: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Line through citation if not in conformance and not considered. Include copy of this form in next communication to applicant.	
* If an asterisk is placed beside the reference number, a copy is not provided because the reference was previously cited by or submitted to the PTO in a prior application that is identified in the statement and relied upon for an earlier filing date under 35 U.S.C. 120. 37 C.F.R. 1.98(d), or a copy is not provided per the Office waiver published in the Official Gazette on August 5, 2003.	
TITLE: IN-SITU INTERFEROMETER ARRANGEMENT	